

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Cook et al.

Serial No.: 09/751,355

Filed: December 28, 2000

Title: System And Method For Testing a Micro-Electronic Device Using A Dual Probe Technique

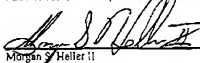
Group Art Unit: 2829

Examiner: R. Kobert

Attorney Docket No.: BUR9-2000-0172-US1  
(02016-00115)

☒ CERTIFICATION OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is being facsimile transmitted to the United States Patent and Trademark Office. Fax No. 703-872-9319, on the date shown below.

 8/12/03  
Morgan S. Heiler II Date

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

August 12, 2003

**RESPONSE TO FINAL OFFICE ACTION**  
**UNDER 37 CFR § 1.116**

This is in response to the Office Action (paper no. 8) mailed from the United States Patent and Trademark Office on June 17, 2003, with respect the above-identified application. Amendments to the Claims and Remarks concerning the Office Action appear in the sections that follow.